

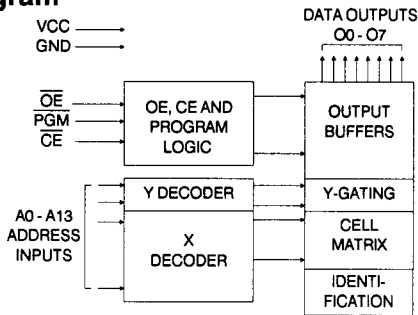
Features

- Low Power CMOS Operation
100 μ A max. Standby
30 mA max. Active at 5 MHz
- Fast Read Access Time - 120ns
- Wide Selection of JEDEC Standard Packages Including OTP
28-Lead 600 mil Cerdip and OTP Plastic DIP
32-Pad OTP PLCC
- 5V \pm 10% Supply
- High Reliability CMOS Technology
2000V ESD Protection
- Fast Programming - 4ms/byte (typical)
- Two-line Control
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

**128K (16K x 8)
UV
Erasable
CMOS
EPROM**

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Block Diagram



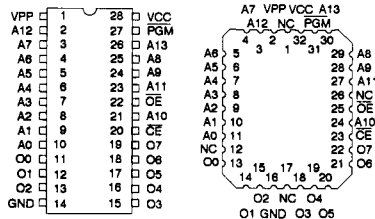
Description

The AT27C128 chip is a low-power, high performance 131,072 bit Ultraviolet Erasable and Electrically Programmable Read Only Memory (EPROM) organized 16K x 8. It requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 120ns, eliminating the need for speed reducing WAIT states on high performance microprocessor systems.

Atmel's 1.5 micron CMOS technology provides optimum speed, low power and high noise immunity. Power consumption is typically only 10mA in Active Mode and less than 10 μ A in Standby. In addition to the speed, power and reliability advantages of the CMOS process, the CMOS technology is an extension of Atmel's high quality and highly manufacturable floating poly EPROM technology.

Pin Configurations

Pin Name	Function
A0-A13	Addresses
O0-O7	Outputs
CE	Chip Enable
OE	Output Enable
PGM	Program Strobe
NC	No Connect



Note: PLCC package Pins 1 and 17 are DON'T CONNECT





Description (Continued)

The AT27C128 comes in a choice of industry standard JEDEC-approved packages including; 32-pin DIP in ceramic or one time programmable (OTP) plastic, and 32-pin OTP plastic J-leaded chip carrier (PLCC). All devices feature two line control (\overline{CE} , \overline{OE}) to give designers the flexibility to prevent bus contention.

With high density 16K byte storage capability, the AT27C128 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's 27C128 has additional features to ensure high quality and efficient production use. The Fast Programming Algorithm reduces the time required to program the part and guarantees reliable programming. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

Erasure Characteristics

The entire memory array of the AT27C128 is erased (all outputs read as V_{OH}) after exposure to ultraviolet light at a wavelength of 2537Å. Complete erasure is assured after a minimum of 20 minutes exposure using 12,000 $\mu\text{W}/\text{cm}^2$ intensity lamps spaced one inch away from the chip. Minimum erase time for lamps at other intensity ratings can be calculated from the minimum integrated erasure dose of 15W•sec/cm². To prevent unintentional erasure, an opaque label is recommended to cover the clear window on any UV erasable EPROM which will be subjected to continuous fluorescent indoor lighting or sunlight.

Operating Modes

MODE \ PIN	\overline{CE}	\overline{OE}	PGM	Ai	V _{PP}	V _{CC}	Outputs
Read	V _{IL}	V _{IL}	V _{IH}	Ai	X ⁽¹⁾	V _{CC}	DOUT
Output Disable	V _{IL}	V _{IH}	V _{IH}	X	X	V _{CC}	High Z
Standby	V _{IH}	X	X	X	X ⁽⁵⁾	V _{CC}	High Z
Fast Program ⁽²⁾	V _{IL}	V _{IH}	V _{IL}	Ai	V _{PP}	V _{CC}	DIN
PGM Verify	V _{IL}	V _{IL}	V _{IH}	Ai	V _{PP}	V _{CC}	DOUT
PGM Inhibit	V _{IH}	X	X	X	V _{PP}	V _{CC}	High Z
Product Identification ⁽⁴⁾	V _{IL}	V _{IL}	X	A9 = V _H ⁽³⁾ A0 = V _{IH} or V _{IL} A1-A13 = V _{IL}	V _{CC}	V _{CC}	Identification Code

- Notes:
1. X can be V_{IL} or V_{IH}.
 2. Refer to Programming Characteristics.
 3. V_H = 12.0 ± 0.5V.
 4. Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H

Absolute Maximum Ratings*

Temperature Under Bias.....	-40°C to +85°C
Storage Temperature.....	-65°C to +125°C
Voltage on Any Pin with Respect to Ground.....	-2.0V to +7.0V ⁽¹⁾
Voltage on A9 with Respect to Ground.....	-2.0V to +14.0V ⁽¹⁾
V _{PP} Supply Voltage with Respect to Ground.....	-2.0V to +14.0V ⁽¹⁾
Integrated UV Erase Dose.....	7258 w•sec/cm ²

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Notes:

1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is V_{CC}+0.75V dc which may overshoot to +7.0V for pulses of less than 20ns.

and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code Byte.

5. Standby V_{CC} current (I_{SB}) is specified with V_{PP}=V_{CC}. V_{CC} > V_{PP} will cause a slight increase in I_{SB}.

D.C. and A.C. Operating Conditions for Read Operation

		AT27C128			
		-12	-15	-20	-25
Operating Temperature (Case)	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C	0°C - 70°C
	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C
V _{CC} Power Supply		5V ± 10%	5V ± 10%	5V ± 10%	5V ± 10%

D.C. and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
I _{LI}	Input Load Current	V _{IN} = -0.1V to V _{CC} + 1V		10	μA
I _{LO}	Output Leakage Current	V _{OUT} = -0.1V to V _{CC} + 0.1V		10	μA
I _{PP1} (2)	V _{PP} (1) Read/Standby Current	V _{PP} = 3.8 to V _{CC} + 0.3V		10	μA
I _{SB}	V _{CC} (1) Standby Current	I _{SB1} (CMOS) CE = V _{CC} -0.3 to V _{CC} + 1.0V	Com.	100	μA
			Ind.,Mil.	200	μA
		I _{SB2} (TTL) CE = 2.0 to V _{CC} + 1.0V	Com.	2	mA
			Ind.,Mil.	3	mA
I _{CC}	V _{CC} Active Current	f = 5MHz, I _{OUT} = 0mA, CE = V _{IL}	Com.	30	mA
			Ind.,Mil.	40	mA
V _{IL}	Input Low Voltage		-0.6	0.8	V
V _{IH}	Input High Voltage		2.0	V _{CC} + 1	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1mA		.45	V
V _{OH}	Output High Voltage	I _{OH} = -100μA		V _{CC} -0.3	V
		I _{OH} = -2.5mA		3.5	V
		I _{OH} = -400μA		2.4	V

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Notes: 1. V_{CC} must be applied simultaneously or before V_{PP}, and removed simultaneously or after V_{PP}.

2. V_{PP} may be connected directly to V_{CC}, except during programming. The supply current would then be the sum of I_{CC} and I_{PP}.

A.C. Characteristics for Read Operation

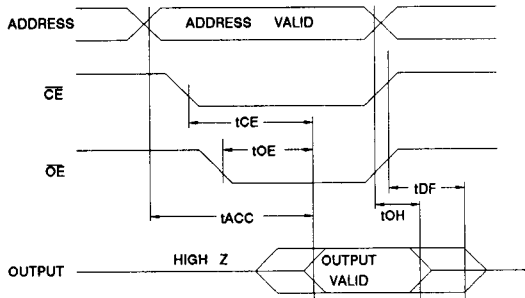
			AT27C128								
			-12		-15		-20		-25		Units
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	
t _{ACC} (4)	Address to Output Delay	CE = OE = V _{IL}	Com.	120	150	200	250	ns			
			Ind.	120	150	200	250	ns			
t _{CE} (3)	CE to Output Delay	OE = V _{IL}		120	150	200	250	ns			
t _{OE} (3,4)	OE to Output Delay	CE = V _{IL}		60	70	75	100	ns			
t _{DF} (2,5)	OE or CE High to Output Float	CE = V _{IL}		50	50	55	60	ns			
t _{OH}	Output Hold from Address, CE or OE, whichever occurred first	CE = OE = V _{IL}		0	0	0	0	ns			

Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.





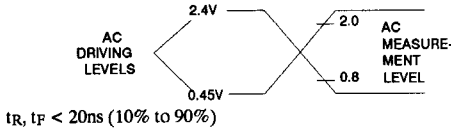
A.C. Waveforms for Read Operation ⁽¹⁾



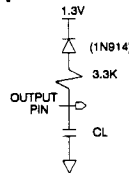
Notes:

1. Timing measurement references are 0.8V and 2.0V. Input AC driving levels are 0.45V and 2.4V, unless otherwise specified.
2. tDF is specified from \overline{OE} or \overline{CE} , whichever occurs first. Output float is defined as the point when data is no longer driven.
3. \overline{OE} may be delayed up to tCE-tOE after the falling edge of \overline{CE} without impact on tCE.
4. \overline{OE} may be delayed up to tACC-tOE after the address is valid without impact on tACC.
5. This parameter is only sampled and is not 100% tested.

Input Test Waveforms and Measurement Levels



Output Test Load



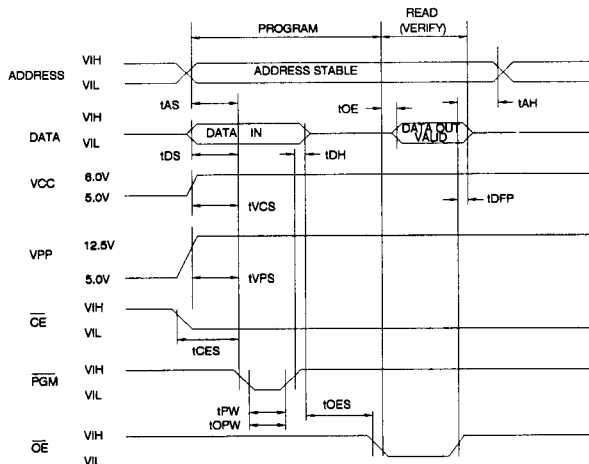
Note: $C_L = 100\text{pF}$ including jig capacitance.

Pin Capacitance ($f = 1\text{MHz}$ $T = 25^\circ\text{C}$) ⁽¹⁾

	Typ	Max	Units	Conditions
C _{IN}	4	6	pF	V _{IN} = 0V
C _{OUT}	8	12	pF	V _{OUT} = 0V

Notes: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

Programming Waveforms ⁽¹⁾



Notes:

1. The Input Timing Reference is 0.8V for V_{IL} and 2.0V for V_{IH}.
2. tOE and tDFP are characteristics of the device but must be accommodated by the programmer.
3. When programming the AT27C128 a 0.1μF capacitor is required across V_{PP} and ground to suppress spurious voltage transients.

